

Search Notes**Application/Control No.**

10/081,863

Examiner

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Applicant(s)/Patent under Reexamination

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Art Unit

2134

SEARCHED

Class	Subclass	Date	Examiner
705	12	11/20/2005	ECT
726	26	11/20/2005	ECT
713	156	11/20/2005	ECT
380	28	8/14/2006	ECT
705	12	8/14/2006	ECT
726	26	8/14/2006	ECT
713	156	8/14/2006	ECT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES, INVENTOR	11/20/2005	ECT
STIC SEARCH EIC 2100	11/20/2005	ECT
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	8/14/2006	ECT

INTERFERENCE SEARCHED

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